



April 1998

FDS6680

Single N-Channel Logic Level PWM Optimized PowerTrench[™] MOSFET

General Description

Features

This N-Channel Logic Level MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

The MOSFET features faster switching and lower gate charge than other MOSFETs with comparable RDS(ON) specifications.

The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

- $\begin{array}{cccc} \text{11.5 A, 30 V. } \text{R}_{\text{DS(ON)}} = 0.010 \; \Omega \; @ \; \text{V}_{\text{GS}} = 10 \; \text{V} \\ \text{R}_{\text{DS(ON)}} = 0.015 \; \Omega \; @ \; \text{V}_{\text{GS}} = 4.5 \; \text{V}. \end{array}$
- Optimized for use in switching DC/DC converters with PWM controllers.
- Very fast switching.
- Low gate charge (typical Qg = 19 nC).

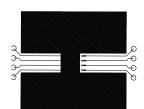
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Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS					-
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		23		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{\rm DS} = 24 \text{V}, V_{\rm GS} = 0 \text{V}$			1	μA
		$T_{J} = 55^{\circ}C$			10	μA
	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
	Gate - Body Leakage, Reverse	$V_{gs} = -20 \text{ V}, V_{ps} = 0 \text{ V}$			-100	nA
ON CHARAC	CTERISTICS (Note 2)				1	•
V _{GS(th)}	Gate Threshold Voltage	$V_{\rm DS} = V_{\rm GS}, \ I_{\rm D} = 250 \ \mu {\rm A}$	1	1.7	3	V
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Temp.Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		-5		mV/ºC
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 11.5 A		0.0085	0.01	Ω
		T, =125°C		0.014	0.017	
		$V_{GS} = 4.5 \text{ V}, I_D = 9.5 \text{ A}$		0.0125	0.015	
I _{D(ON)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$	50			Α
g _{FS}	Forward Transconductance	$V_{\rm DS} = 15 \text{ V}, \ I_{\rm D} = 11.5 \text{ A}$		40		S
DYNAMIC C	HARACTERISTICS					•
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		2070		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		510		pF
C _{rss}	Reverse Transfer Capacitance			235		pF
SWITCHING	CHARACTERISTICS (Note 2)					
t _{D(on)}	Turn - On Delay Time	$V_{DS} = 15 \text{ V}, \ \text{I}_{D} = 1 \text{ A}$		13	21	ns
t,	Turn - On Rise Time	$V_{GS} = 10 \text{ V}$, $R_{GEN} = 6 \Omega$		10	18	ns
t _{D(off)}	Turn - Off Delay Time			36	58	ns
t,	Turn - Off Fall Time			13	23	ns
Q _g	Total Gate Charge	$V_{DS} = 15 \text{ V}, \ \text{I}_{D} = 11.5 \text{ A},$		19	27	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		7		nC
Q _{gd}	Gate-Drain Charge			6		nC
DRAIN-SOUI	RCE DIODE CHARACTERISTICS AND MAXI	MUM RATINGS				
l _s	Maximum Continuous Drain-Source Diode Forward Current				2.1	Α
V _{SD}	Drain-Source Diode Forward Voltage $V_{GS} = 0 \text{ V}, I_S = 2.1 \text{ A}$ (Note 2)				1.2	V

Notes:

1. R_{BAR} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BAC} is guaranteed by design while R_{BAC} is determined by the user's board design.



a. 50°C/W on a 1 in² pad of 2oz copper.

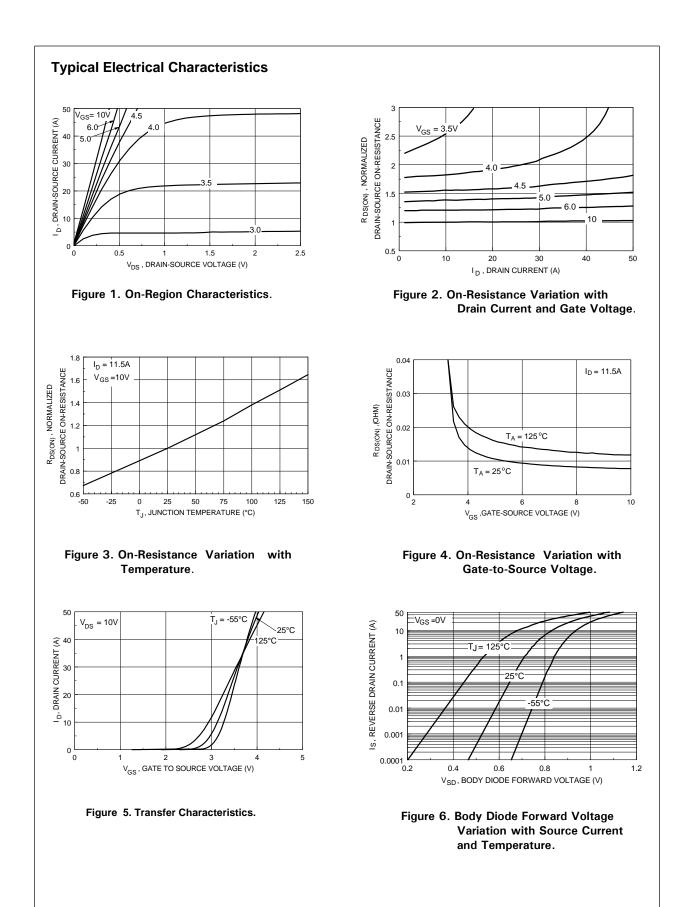


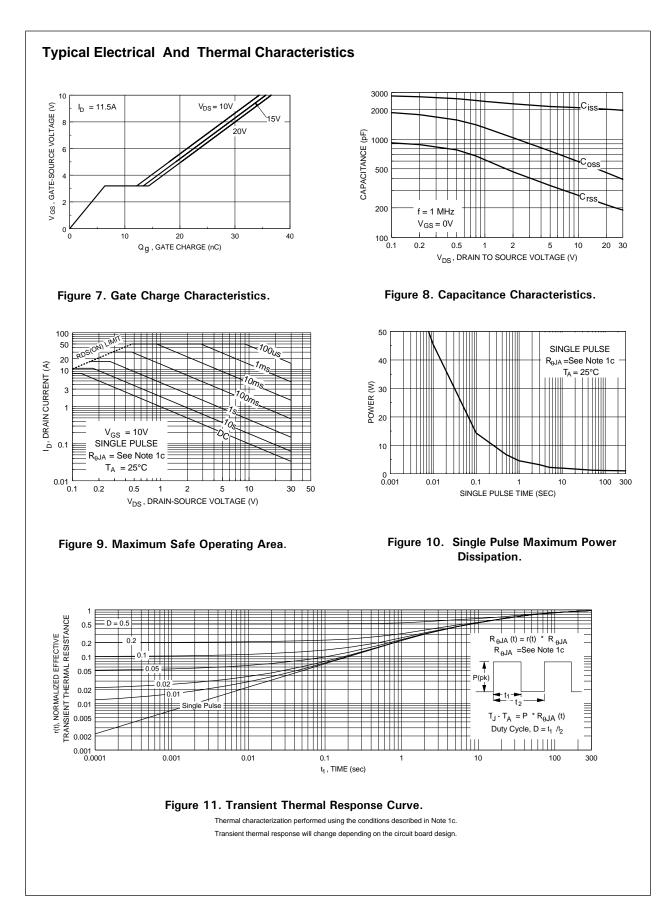


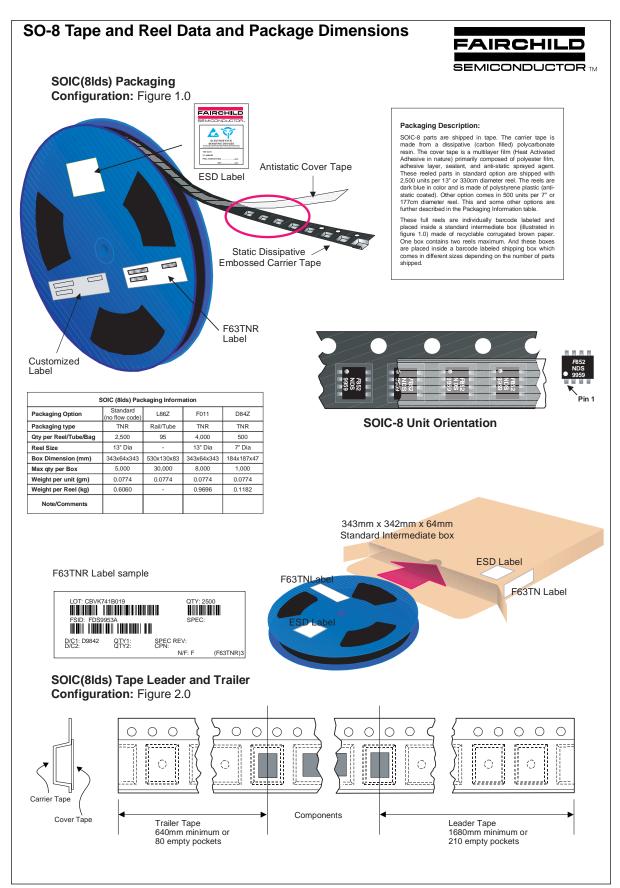


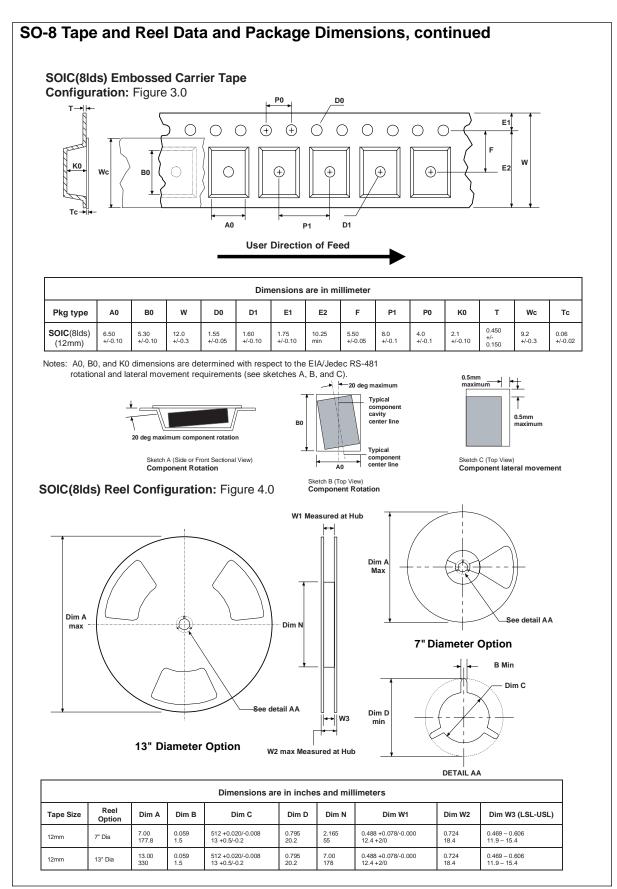
Scale 1 : 1 on letter size paper

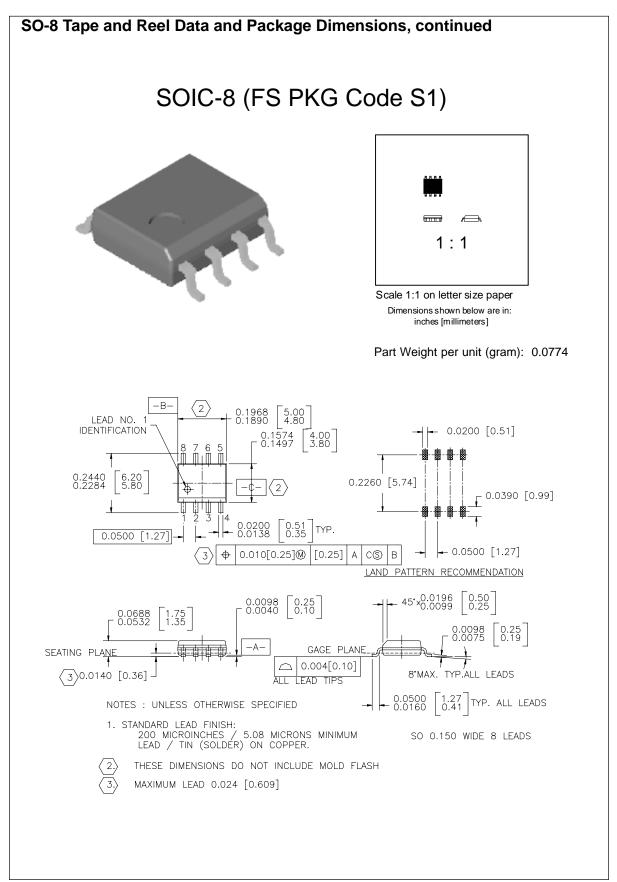
2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.











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